Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/537,548	SAKAI ET AL.	
Examiner	Art Unit	_
Dinh Q. Nguyen	3752	

	SEARCHED						
С	lass	Subclass		Date	Examiner		
2	<b>5</b> 1_	228					
		249					
		248					
		246					
		243					
		225.1					
		227	9	17/07	WN		
					-		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
_					
	<u></u>				

SEARCH NOT (INCLUDING SEARCH		) .
	DATE	EXMR
SAST SBARUH ATTACHED		
		\ \sigma \
	9/12/0	$\mathcal{M}\mathcal{M}$
	١	
•		
	!	,